

Implementation-independent test generation for a large class of faults in RISC processor modules

Jenihhin, Maksim; Oyeniran, Adeboye Stephen; Raik, Jaan; Ubar, Raimund-Johannes 24th Euromicro Conference on Digital System Design (DSD) 2021 <https://doi.org/10.1109/DSD53832.2021.00090>